Notice of References Cited

Application/Control No. 10/059,173	Applicant(s)/l Reexamination HAN ET AL.	Applicant(s)/Patent Under Reexamination HAN ET AL.	
Examiner	Art Unit		
Paulos M. Natnael	2614	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,583,575 A	12-1996	Arita et al.	348/451
	В	US-6,594,313 B1	07-2003	Hazra et al.	375/240.16
	С	US-6,104,439 A	08-2000	Jeong et al.	348/699
	D	US-5,475,438 A	12-1995	Bretl, Wayne E.	348/452
	Е	US-6,118,489 A	09-2000	Han et al.	348/452
	F	US-6,414,719 B1	07-2002	Parikh, Sandip	348/448
	G	US-5,488,430 A	01-1996	Hong, Sung H.	348/699
	Н	US-5,943,099 A	08-1999	Kim, Young-taek	348/448
	1	US-6,577,345 B1	06-2003	Lim et al.	348/452
	J	US-5,793,435	08-1998	Ward et al.	348/448
	К	US-6,731,342 B2	05-2004	Shin et al.	348/452
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R	-				
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.